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Application/Control N	lo.

Applicant(s	)/Patent	under
Reexaminat	ion	

OKABE ET AL.

10/769,795

Examiner

Art Unit 1756

Shean C. Wu

SEARCHED				
Class	Subclass	Date	Examiner	
428	1.1	3/6/2005	SW	
252	299.63			
	299.66			
	299.67			
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
428	1.1	3/6/2005	sw	
252	299.63			
	299.66			
299.67				

SEARCH N (INCLUDING SEARC		·)
	DATE	EXMR
update structure search, see attachment	3/6/2005	sw
inventor search (palm)		